



2872

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No. : 10/085,507
Applicant : John W. Orcutt
Filed : 02/26/2002
TC/A.U. : 2872
Examiner : Shafer, Ricky D.

Confirmation No. 8689

Docket No. : TI-32675
Customer No. : 23494

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INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97 & 1.98

Commissioner for Patents
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William B. Kempler *10/7/03*
William B. Kempler Date

Dear Sir:

In the matter of the above identified application, Applicants are submitting herewith copies of documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

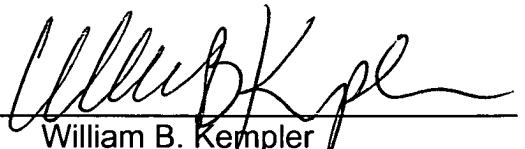
In accordance with 37 CFR 1.97 (c), this Information Disclosure Statement is being submitted before the mailing date of a Final Action or a Notice of Allowance and is accompanied by the following certification specified in 37 CFR 1.97 (e).

On information and belief, I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Pursuant to 37 CFR 1.97 (d), Applicants respectfully petition that this Information Disclosure Statement be considered by the Examiner.

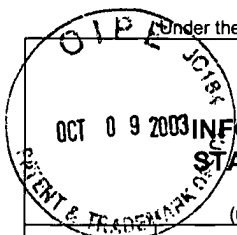
Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the Deposit Account No. 20-0668 of Texas Instruments Incorporated, and please credit any excess fees to such Deposit Account. **This form is submitted in triplicate.**

Respectfully submitted,
Texas Instruments Incorporated

By 
William B. Kempler
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete If Known

Application Number	10/085,507
Filing Date	02/26/2002
First Named Inventor	John W. Orcutt
Group Art Unit	2872
Examiner Name	Shafer, Ricky D.
Attorney Docket No.	TI-32675

Sheet 1 of 1

U.S. PATENT DOCUMENTS

Exam. Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
	AA	6,094,293		Yokoyama, et al	07/25/2000	
	AB					
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FOREIGN PATENT DOCUMENTS

Exam. Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ² (if known)				
	BA	EP	0 962 796 A2		Congdon, et al	12/08/1999		
	BB	DE	42 35 593 A1		Reicheneder	10/21/1993		
	BC							
	BD							
	BE							
	BF							
	BG							
	BH							

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Exam. Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	CA	KIM, "A laser-based 2-dimensional angular deflection measurement system for tilting microplates", Sensors Actuators, 86 (2000), pages 141-147, Elsevier, BNSDOCID: <XP 4224542A 1 >.	
	CB	CHUNG, "Measurements of a fabricated micro mirror using a lateral-effect position-sensitive photodiode", Electronics, IEEE Inc. New York, U.S., vol. 45, no. 6, 1 December 1998 (1998-12-01), pages 861-865, XP000789096, ISSS: 0278-0046, abstract, pages 861-865.	
	CC	TUANTRANONT, "Smart phase-only micromirror array fabricated by standard CMOS process", Proceedings IEEE Thirteenth Annual International Conference on Micro Electro Mechanical Systems, Miyazaki, Japan, 23-27 Jan. 2000, pages 455-460.	
	CD		
	CE		
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	CH		

Examiner Signature	Date Considered
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

US and Foreign Patent Documents: ¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Other Prior Art/Non-Patent Literature Documents: ¹Unique citation designation number. ²Applicant is to place a check mark here if English Translation is attached.



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Datum/Date

08.07.03

Zeichen/Ref./Réf. TI-32675 EP	Anmeldung Nr./Application No./Demande n°/Patent Nr./Patent No./Brevet n°. 02100191.2-2217-
Anmelder/Applicant/Demandeur/Patentinhaber/Proprietor/Titulaire Texas Instruments Incorporated	

COMMUNICATION

The European Patent Office herewith transmits as an enclosure the European search report for the above-mentioned European patent application.

If applicable, copies of the documents cited in the European search report are attached.

☒ Additional set(s) of copies of the documents cited in the European search report is (are) enclosed as well.

The following specifications given by the applicant have been approved by the Search Division:

☒ abstract

☒ title

☐ The abstract was modified by the Search Division and the definitive text is attached to this communication.

The following figure will be published together with the abstract: 1

Received

14 JUL 2003
Impetus



REFUND OF THE SEARCH FEE

If applicable under Article 10 Rules relating to fees, a separate communication from the Receiving Section on the refund of the search fee will be sent later.



DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
D,X	EP 0 962 796 A (TEXAS INSTRUMENTS INC) 8 December 1999 (1999-12-08) * column 6, paragraph 18 - paragraph 19 *	1-4,7,8,11	G02B26/08
Y	* column 7, paragraph 24 - column 8, paragraph 27 * * column 8, paragraph 31 - column 9, paragraph 33; figures 1,3,7,7A *	1,5,6	
Y	US 6 094 293 A (OTA HITOSHI ET AL) 25 July 2000 (2000-07-25) * column 2, line 12 - line 17 * * column 6, line 43 - column 7, line 42 * * column 12, line 9 - line 26; figures 1,12 *	1,5,6	
X	DE 42 35 593 A (TECHNOLOGIE PLATTFORM THUERING) 21 October 1993 (1993-10-21) * abstract * * column 2, line 19 - line 35; figures 1,2 *	1,2,7,9-11	
X	KIM H ET AL: "A laser-based 2-dimensional angular deflection measurement system for tilting microplates" SENSORS AND ACTUATORS A, ELSEVIER SEQUOIA S.A., LAUSANNE, CH, vol. 86, no. 1-2, 30 October 2000 (2000-10-30), pages 141-147, XP004224542 ISSN: 0924-4247 * abstract * * page 141 " 1.Introduction" * * pages 142-143 "3.Measurement Systems" *	1,2,5-7,9-11	G02B
The present search report has been drawn up for all claims			TECHNICAL FIELDS SEARCHED (Int.Cl.7)
Place of search MUNICH		Date of completion of the search 30 June 2003	Examiner Besser, V
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document			

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EPO FORM 1503 03.82 (P04C01)



DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
X	CHUNG S-W ET AL: "MEASUREMENTS OF A FABRICATED MICRO MIRROR USING A LATERAL-EFFECT POSITION-SENSITIVE PHOTODIODE" IEEE TRANSACTIONS ON INDUSTRIAL ELECTRONICS, IEEE INC. NEW YORK, US, vol. 45, no. 6, 1 December 1998 (1998-12-01), pages 861-865, XP000789096 ISSN: 0278-0046 * abstract * * page 861 "I. Introduction" * * page 863 "IV. Measurement of Static and Dynamic Characteristics" * * figures 1,2 *	1,2,5	
A	TUANTRANONT A ET AL: "Smart phase-only micromirror array fabricated by standard CMOS process" PROCEEDINGS IEEE THIRTEENTH ANNUAL INTERNATIONAL CONFERENCE ON MICRO ELECTRO MECHANICAL SYSTEMS, MIYAZAKI, JAPAN, 23-27 JAN. 2000, pages 455-460, XP010377170 ISBN: 0-7803-5273-4 * page 455 "CMOS Micromirror" * * page 457 "Electro-Thermal Analysis" * * figure 2 *	1,2,5,9	
			TECHNICAL FIELDS SEARCHED (Int.Cl.7)
The present search report has been drawn up for all claims			
Place of search MUNICH		Date of completion of the search 30 June 2003	Examiner Besser, V
CATEGORY OF CITED DOCUMENTS X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons & : member of the same patent family, corresponding document			

2
EPO FORM 1503 03.02 (P04001)

**ANNEX TO THE EUROPEAN SEARCH REPORT
ON EUROPEAN PATENT APPLICATION NO.**

EP 02 10 0191

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report.
The members are as contained in the European Patent Office EDP file on
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30-06-2003

Patent document cited in search report		Publication date	Patent family member(s)	Publication date
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			JP 2000010029 A	14-01-2000
			US 6295154 B1	25-09-2001
			US 6430332 B1	06-08-2002
			US 2002018615 A1	14-02-2002
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EPO FORM P0459

For more details about this annex : see Official Journal of the European Patent Office, No. 12/82